Amendment under Article 34

To: Examiner of the Patent Office, Mitsuhiro YOSHINO

1. Identification of the International Application

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4. Item to be Amended Claims

5. Subject Matter of Amendment:

- (1) With regard to Claim 1 of Scope of claim for Patent at page 12, "A Group III nitride semiconductor light-emitting element including an n-type contact layer of n-type GaN, an n-type clad layer of n-type Al_xGa_{1-x-y}In_yN (0<x<1, 0≤y<1, 0<x+y<1), an active layer, a p-type clad layer, and a p-type contact layer, comprising: a crack-preventing layer of n-type GaN provided between the n-type contact layer and the n-type clad layer, wherein the crack-preventing layer has a dopant concentration lower than that of the n-type contact layer." is amended to "A Group III nitride semiconductor light-emitting element including an n-type contact layer of n-type GaN, an n-type clad layer of n-type Al_xGa_{1-x}N (0<x<1), an active layer, a p-type clad layer, and a p-type contact layer, comprising: a crack-preventing layer of n-type GaN provided between the n-type contact layer and the n-type clad layer, wherein the crack-preventing layer has a dopant concentration lower than that of the n-type contact layer."
- (2) With regard to Claim 7 of Scope of claim for Patent at pages 12-13, "A method of manufacturing a semiconductor light-emitting element having a multilayered structure constituted by sequentially stacking layers of Group III nitride semiconductors one upon another on a substrate, the method comprising: an n-type contact-layer forming step of forming an n-type contact layer of n-type GaN, and a crack-preventing layer forming step of forming a crack-preventing layer of n-type GaN, the crack-preventing layer having a dopant concentration lower than that of the n-type contact layer." is amended to "A method of manufacturing a semiconductor light-emitting element having a multilayered structure constituted by sequentially stacking layers of Group III nitride semiconductors one upon another on a substrate, the method comprising: an n-type contact-layer forming step of forming an n-type contact layer of n-type GaN, and a crack-preventing layer forming step of forming a crack-preventing layer for n-type GaN, the crack-preventing layer having a dopant

concentration lower than that of the n-type contact layer, and a clad layer forming step of forming an n-type clad layer of n-type $Al_xGa_{1-x}N$ (0<x<1) on the crack-preventing layer."